TECHNICAL REPORT

ISO/TR 18231

First edition
2016-05-01

Iron ores — Wavelength dispersive X-ray fluorescence spectrometers — Determination of precision

Minerais de fer — Spectromètres à fluorescence à rayons X à longueur d'onde dispersive — Détermination de la précision

Reference number
ISO/TR 18231:2016(E)

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Foreword

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The committee responsible for this document is ISO/TC 102, *Iron ore and direct reduced iron*, Subcommittee SC 2, *Chemical analysis.*

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Introduction

If an X-ray fluorescence spectrometer is to be used for precise analyses, it needs to be functioning correctly to specification, that is, the errors associated with the various functions of the instrument have to be very small. It is important therefore that the spectrometer be tested to ensure that it is indeed functioning to deliver the required precision. The objective of this Technical Report is to set out tests that can be used to ascertain the extent of the errors and to suggest procedures for their rectification. These tests are not used to ascertain whether the instrument is operating optimally but to determine whether the instrument is capable of giving a preselected precision.

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Iron ores — Wavelength dispersive X-ray fluorescence spectrometers — Determination of precision

1 Scope

This Technical Report describes methods of test that can be applied to wavelength dispersive X-ray fluorescence (WD-XRF) spectrometers to ensure that the spectrometers are functioning in a manner that allows precise analyses to be made.

The tests outlined are designed to measure the errors associated with the operation of certain parts of the spectrometer. They are not designed to check every part of the spectrometer but only those parts that may be the common sources of error.

It is assumed that the performance of the instrument has been optimized according to the manufacturer's instructions. For all tests, the two-theta angle should be carefully set for the line being measured. The pulse height window should be set according to the manufacturer's instructions and should have a broad setting which may also include the escape peak for gas proportional counters. The instrument and detector gas environment should be as specified by the manufacturer, as should the power supply to the instrument.

NOTE Where no distinction has been made, it is assumed that a test is applicable to both sequential and simultaneous spectrometers.

2 Frequency of testing

Testing is not required to be carried out with each batch of analyses. The frequency of testing varies depending on the test involved. Table 1 lists the suggested frequency with which each test should be carried out. Where specific problems are encountered, more frequent testing may be required and remediation work performed.

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